Field Emission Electron Microscope (FESEM)





Probe morphology of nanostructured materials in film as well as powder form along with elemental analysis of **nanoparticles**, **alloys**, **porous materials**, **ceramics**, **polymers** etc.

Instrument parameters:

Resolution	0.8 nm at 15kV and
	1.4 nm at 1kV
Magnification	up to 2 x 10 ⁶
Operating voltage	20V to 30KV
Number of slots for	9
mounting samples	

Additional attachments

- i) Energy dispersive X-ray (EDX) analysis for elemental mapping [Energy resolution \leq 127 eV at MnK α ; Sensitivity \sim 0.01 wt%]
- ii)Variable Pressure (VP) Mode (<500 Pa)
- iii) 80-mm airlock allows quick transfer of the samples without breaking the system vacuum
- iii) Plasma cleaning the sample chamber for removing contamination



